

# Mini PCI Express & mSATA Connector

1 Scope:

1.1 Contents

This specification covers the requirements for product performance, test methods and quality assurance provisions of MINI PCI Express Connector. Applicable product description and part numbers are as shown in Appendix 1.

### 2. Applicable Documents:

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1 TYCO Specifications:

A. 109-5000 Test Specification, General Requirements for Test Methods

B. 501-99107 Test Report

2.2 Commercial Standards and Specifications:

A. MIL-STD-202

B. Mini PCI Express Card Electromechanical Specification Revision 1.0

C. EIA-364



.,	Daguiramanta	
3.	Requirements	

#### 3.1 Design and Construction:

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2 Materials:

A. Contact:

Copper Alloy

Finish:

Contact area: Gold Flash

Tine area: Gold Flash

Underplate: Nickel Plated

B. Housing:

Thermo plastic UL94V-0

C. Solder Peg:

Copper Alloy, Tin Plated over Ni plate.

D. Latch:

Steel, Tin Plated over Ni plate

3.3 Ratings:

A. Voltage Rating: 50 VAC

B. Current Rating: 0.5 A

C. Temperature Rating: -55°C to 85°C

D. Reflow Peak Temperature: 260°C MAX.

3.4 Performance Requirements and Test Descriptions:

The product shall be designed to meet the electrical, mechanical and environmental performance requirements specified in Fig. 1. All tests shall be performed in the room temperature, unless otherwise specified.

Rev. C2 2 of 7



## 3.5 Test Requirements and Procedures Summary

Para.	Test Items	Requirements	Procedures			
3.5.1	Examination of Product	Meets requirements of product	Visual inspection			
		drawing	No physical damage			
Electrical Requirements						
3.5.2	Termination Resistance	55 m Ω Max. (Initial)	Subject mated contacts assembled in			
	(Low Level)	$\Delta R$ =20 m $\Omega$ Max. (Final)	housing to closed circuit current of 10 mA			
			Max. at open circuit voltage of 20mV Max.			
			obtain resistance value by dividing the			
			measured reading into two.			
			Fig. 3-1.			
			EIA-364-23			
3.5.3	Dielectric withstanding	No creeping discharge nor	0.3 kVAC for 1 minute.			
	Voltage	flashover shall occur.	Test between adjacent circuits of unmated			
		Current leakage: 0.5 mA Max.	connectors.			
			EIA-364-20			
3.5.4	Insulation Resistance	500M Ω Min.(Initial)	Impressed voltage 500 V DC.			
		500M Ω Min.(Final)	Test between adjacent circuits of unmated			
			connectors.			
			EIA-364-21			
3.5.5	Temperature Rising	30 °C Max. under loaded	Measure temperature rising by energized			
		specified current (0.5 A)	current.			
			EIA-364-70 Test method 2			

Fig.1 (CONT.)

Rev. C2 3 of 7



		Mechanical Requiremen	nts				
Para.	Test Items	Requirements	Procedures				
3.5.6 Vibration		No electrical discontinuity	Subject mated connectors				
	(Random)	greater than 1 $\mu$ sec. shall	Vibration Frequency: 10 to 55 Hz				
		occur.	Accelerated Velocity: 30.38m/s <sup>2</sup>				
		$\Delta R=20 \text{ m}\Omega$ Max. (Final)	(3.1G), rms.				
			Vibration Direction: In each of 3 mutually				
			perpendicular planes.				
			Duration: 15 minutes each				
			100 mA applied.				
			Module board should be fixed on the connector mount board or test jig.				
			EIA-364-28 Method VII condition D				
3.5.7	Physical Shock	No electrical discontinuity	Accelerated Velocity: 490 m/s <sup>2</sup> (50 G)				
	(Normal test)	greater than 1 $\mu$ sec.	Waveform: Half sine				
		shall occur.	Duration: 11 m sec.				
		$\Delta R=20 \text{ m}\Omega$ Max. (Final)	Number of Drops: 3 drops each to normal				
			and reversed directions of X, Y and Z				
			axes, totally 18 drops.				
			EIA-364-27 Condition A				
3.5.8	Connector Mating Force	22.5N (2.3kgf) Max.	Operation Speed: 100 mm/min.				
			Measure the force required to mate				
			connectors (In this test, the force required				
			to turn PCB before it engages on lacking,				
			is excluded).				
			EIA-364-13				
3.5.9	Durability	$\Delta R$ =20 m $\Omega$ Max. (Final)	Repeated insertion and extraction of P.C.B				
	(Repeated		to and from the connector with the turns to				
	Mating/Unmating)		lock it and then unlock it for 50 cycles.				
			EIA-364-9				
3.5.10	Durability	No physical damage	No. of cycles: 20 cycles				
	(Preconditioning)						
3.5.11	Reseating	No physical damage	No. of cycles: 3 cycles				
3.5.12	Solderability	Wet Solder Coverage:	Solder Temperature: 245 ± 5 °C				
			Immersion Duration: 3 ± 0.5 seconds				
		95 % Min.	Flux: Alpha 100				

Fig.1 (CONT.)

Rev. C2 4 of 7

Para.Test ItemsRequirements3.5.13Resistance to RefowNo physical damage shallTest connector	Procedures			
	on DC Board			
	OH P.C.BOald			
Soldering Heat occur Temperature is	measured on a soldering			
pad. Fig.3				
Pre-Heat150~:	200°C: 60~180sec.			
Heat 217°C Min	n.: 60~150sec.			
Heat Peak 260	+0/-5°C			
The number of	reflow: 2 times			
3.5.14 Thermal Shock $\Delta R=20 \text{ m}\Omega$ Max. (Final) Mated connected	or			
_55 +0/-3°C /	′ 30 min., 85 +3/-0°C / 30			
min.				
Making this a c	ycle, repeat 10 cycles.			
EIA-364-32, Co	EIA-364-32, Condition A			
3.5.15 Temperature - Humidity Insulation resistance Mated connected	or,			
Cycling 500 M $\Omega$ Min. (final) 25±3 $\sim$ 65±3 $^{\circ}$	C, 50±3~80±3% R.H.			
$\Delta R=20 \text{ m}\Omega$ Max. (Final) 24 cycles				
Cold shock —1	10°C performed			
EIA-364-31				
$3.5.16$ Thermal Cycling $\Delta$ R=20 mΩ Max. (Final) Mated connected	or,			
15±3~85±3°	С			
Ramps: 2°C/mii	n.			
Dwell time: 5mi	n. Min.			
10 Cycle				
$3.5.17$ Temperature Life $\Delta R=20 \text{ m}\Omega$ Max. (Final) Mated connected	or			
(Heat Aging) 115°C, Duration				
EIA-364-17, Me				
3.5.18 Temperature Life No physical damage Mated connected	or			
(Preconditioning) 115°C, Duration	n: 96 hours			
EIA-364-17, Me	ethod A			

Fig. 1 (End)

Rev. C2 5 of 7



## 4. Product Qualification Test Sequence

	Test Group										
Test Examination	1	2	3(b)	4(b)	5	6	7	8	9	10	11
Test Examination		Test Sequence (a)									
Examination of Product	1, 5	1, 3	1, 5, 8	1, 4	1, 3	1, 4	1, 3	1, 3	1, 5, 8, 11	1, 5, 8	1, 5, 8, 11
Termination Resistance (Low Level)			2, 6, 9	2, 5		2, 5			2, 6, 9, 12	2, 6, 9	2, 6, 9, 12
Dielectric withstanding Voltage	2, 6										
Insulation Resistance	3, 7										
Temperature rising		2									
Vibration (Random)			7								
Physical Shock				3							
Connector Mating Force					2						
Durability (Repeated mate/unmate)						3					
Durability (Proconditioning)			3						3	3	3
Reseating									10	7	10
Solderability							2				
Resistance to Reflow Soldering Heat								2			
Temperature Humidity Cycling	4								7		
Thermal Shock									4		
Thermal Cycling											7
Temperature Life (Heat Aging)										4	
Temperature Life (Proconditioning)			4								4

FIG.2

a) Numbers indicate sequence in which the tests are performed.

b) In these test groups, no electrical discontinuity shall occur.

Rev. C2 6 of 7



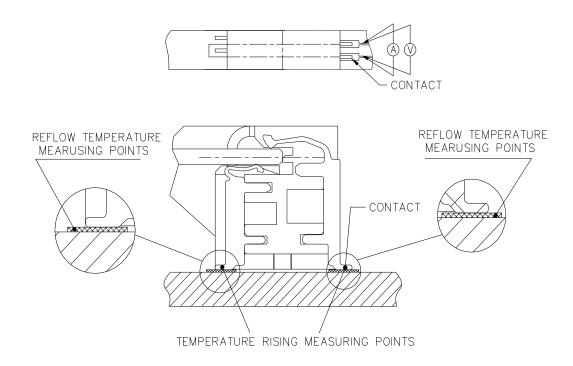
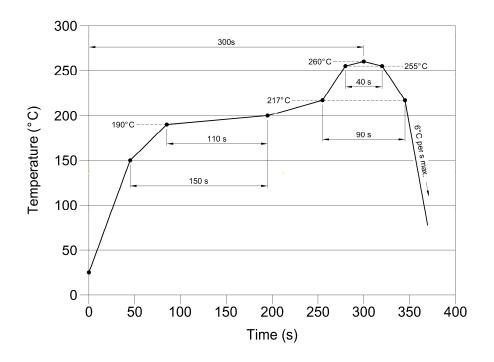


Fig. 3-1 Termination Resistance Measuring points, Temperature Rising Measuring points, and Reflow Temperature Measuring points.



Temperature Profile of Reflow Soldering Figure 4

Rev. C2 7 of 7